nexperia

Quarterly Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

Based on structural similarity

| Supplier | | User Part Number | | | | | | |
|-------------------------------------|--|---|-----------------------------------|-----------|------------|-----------|--|--|
| Nexperia B.V. Name of Laboratory | | IP4256CZ5-W Part Description | | | | | | |
| | | | | | | | | |
| Assembly reliability labs | | SMD package | | | | | | |
| Test | | Test Conditions | Duration | # Lots | # Quantity | # Rejects | | |
| | TEST Pre- and Post-Stress | | | | | | | |
| # 1 | Electrical Test | Tamb = 25 °C | N/A | see below | all parts | see below | | |
| # 2 | PC Preconditioning | JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering | 24 hours 168 hours 3 cycles | 286 | 21480 | 0 | | |
| # 5 | HTRB High Temperature Reverse Bias | MIL-STD-750-1 M1038 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage | 1000 hours | 117 | 9360 | 0 | | |
| # 7 | TC Temperature Cycling | JESD22-A104 -65 °C to Tjmax, not to exceed 150°C | 1000 cycles | 86 | 6880 | 0 | | |
| # 8 | AC Autoclave | JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia) | 96 hours | 86 | 6880 | 0 | | |
| # 9 | H3TRB High Humidity High Temperature Reverse Bias | JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage ^[1] | 1000 hours | 86 | 6880 | 0 | | |
| # 10 | IOL Intermittent Operating Life | MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj = | 1000 hours | n.a. | n.a. | n.a. | | |
| # 20 | RSH Resistance to Solder Heat | JESD22-A111 260 °C ± 5 °C | 10 s | 28 | 840 | 0 | | |
| # 20 | SD | 200 0 - 0 0 | 10.2 | 20 | 040 | 0 | | |
| # 21 | Solderability | J-STD-002 | | 36 | 360 | 0 | | |

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Wafer Fab | Technology | Quantity | Rejects | Failure Rate (FIT) | MTTF (hrs) |
|------------------|------------|----------|---------|--------------------|------------|
| Nexperia DHAM | Protection | 9360 | 0 | 0.45 | 2.20E+09 |
| 51# 11 | | 3300 | 0 | 0:45 | 2.20L |

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